

---

# **Lossy Line Characterization and Modeling for SPICE and IBIS**

**Steve Corey  
TDA Systems, Inc.**

*The Interconnect Modeling Company™*

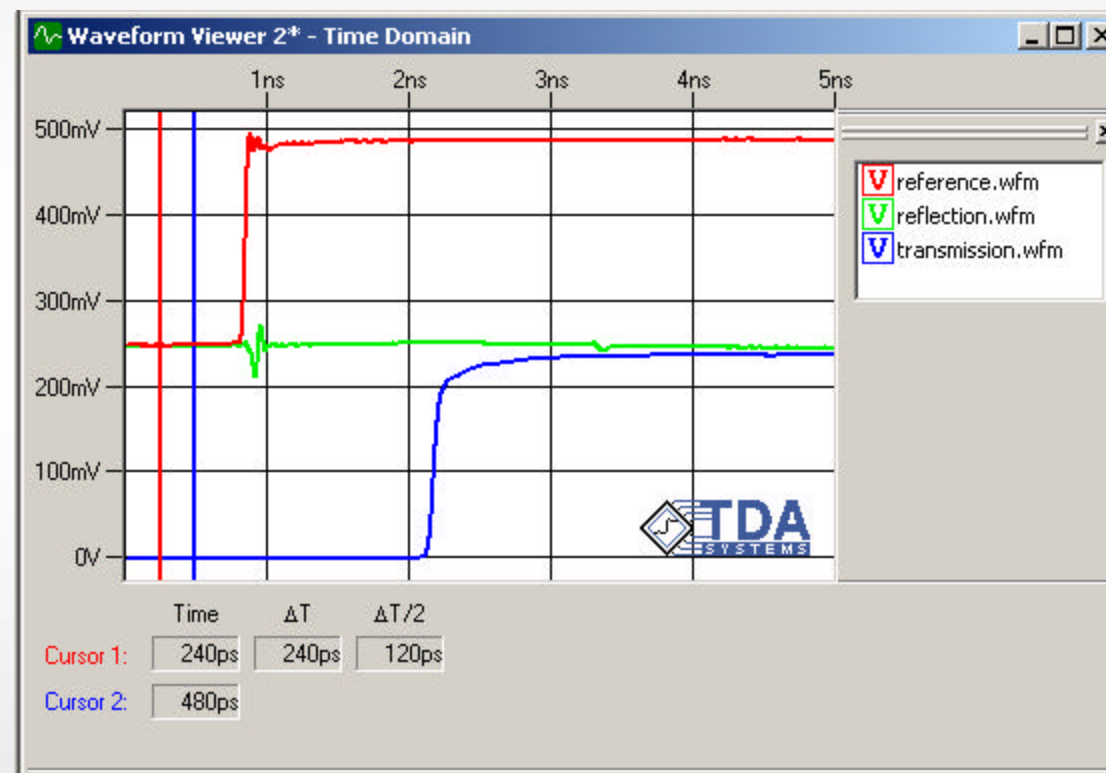


# In This Talk...

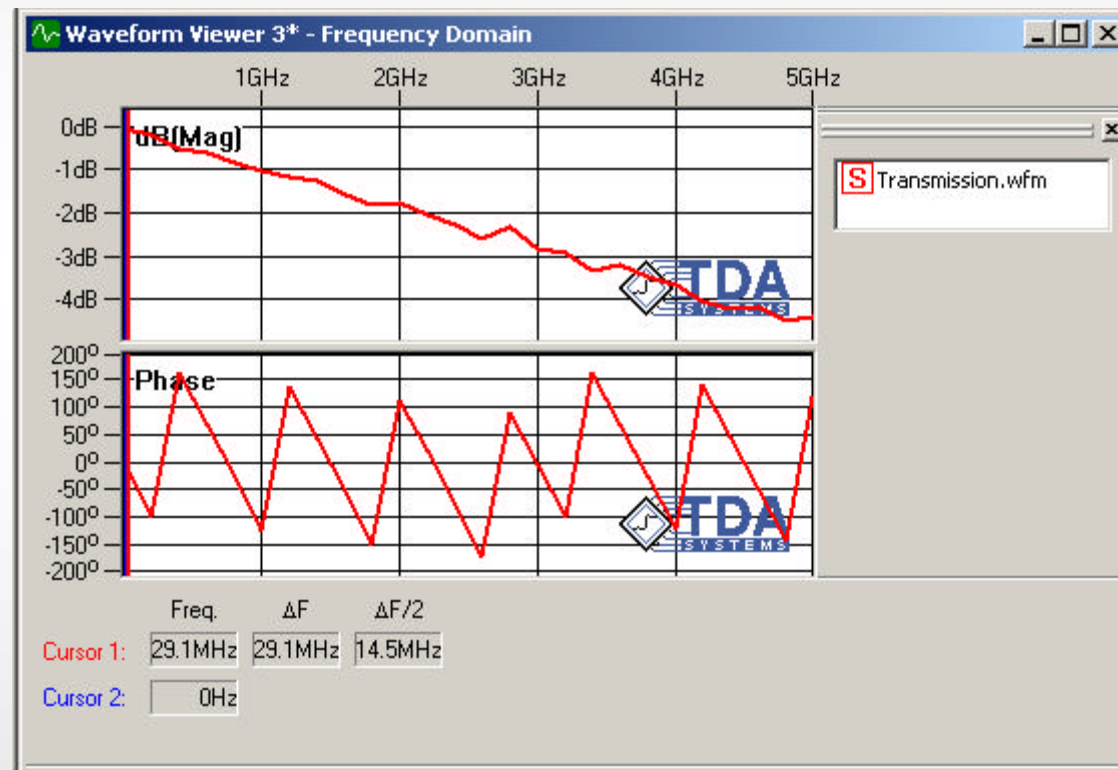
---

- **Examples of loss**
- **Why loss matters**
- **Physical basis for loss**
- **Modeling approaches**
- **Loss modeling issues**
- **Our approach**
- **Results**
- **Conclusions**

# Loss Example: Time Domain



# Loss Example: Frequency Domain



# Why Loss Matters

---

- **Ignoring loss can cause design failures**
  - Data rates too high
  - Drivers too weak
- **Overestimating loss can result in overly conservative designs**
  - Slower than necessary
  - Stronger drive than necessary

# Why Loss is a “Recent” Issue

---

- **Loss is only recently significant in common digital design**
  - Faster rise times and data rates
  - Narrower traces
  - Same old materials...
- **Loss has long been significant in analog design**
  - Frequency-Domain analysis methods
  - Not targeted toward broadband modeling

# Physical Basis for Loss

---

- **Resistance in metal**
  - Varying skin depth causes frequency-dependent resistance
  - Magnetic flux internal to metal causes frequency-dependent inductance
- **Conductance in dielectric**
  - Constant non-zero loss tangent causes frequency-dependent conductance
  - Charges moving within dielectric cause frequency-dependent capacitance

# Different TEM Modeling Approaches

---

- **Lumped**
  - Defined for all frequencies
  - Slow for long lines
- **Distributed**
  - **Based on parameters ( $R_{\text{skin}}$ ,  $G_{\text{dielectric}}$ )**
    - Defined for all frequencies
    - Not as general
  - **Based on RLGC data**
    - General for quasi-TEM
    - Not defined for all frequencies



# Loss Modeling Issues

---

- **Accuracy of model**
  - Defined for sufficient range of frequencies
- **Passivity of model**
  - Cannot generate energy
  - Required for use in a time-domain simulator which handles feedback
  - Requires model to be causal
- **Stability of algorithm**
  - Unstable algorithms can cause passive models to blow up

# Causality in TEM Models

---

- From basic physics, the real and imaginary parts of the dielectric constant are tightly related to ensure causality.
- The same is true of the permeability constant,  $\mu$
- In TEM modeling, this means that R and L are related, and G and C are related
- Models based on RLGC data should address this issue

# Our Model Extraction Approach

---

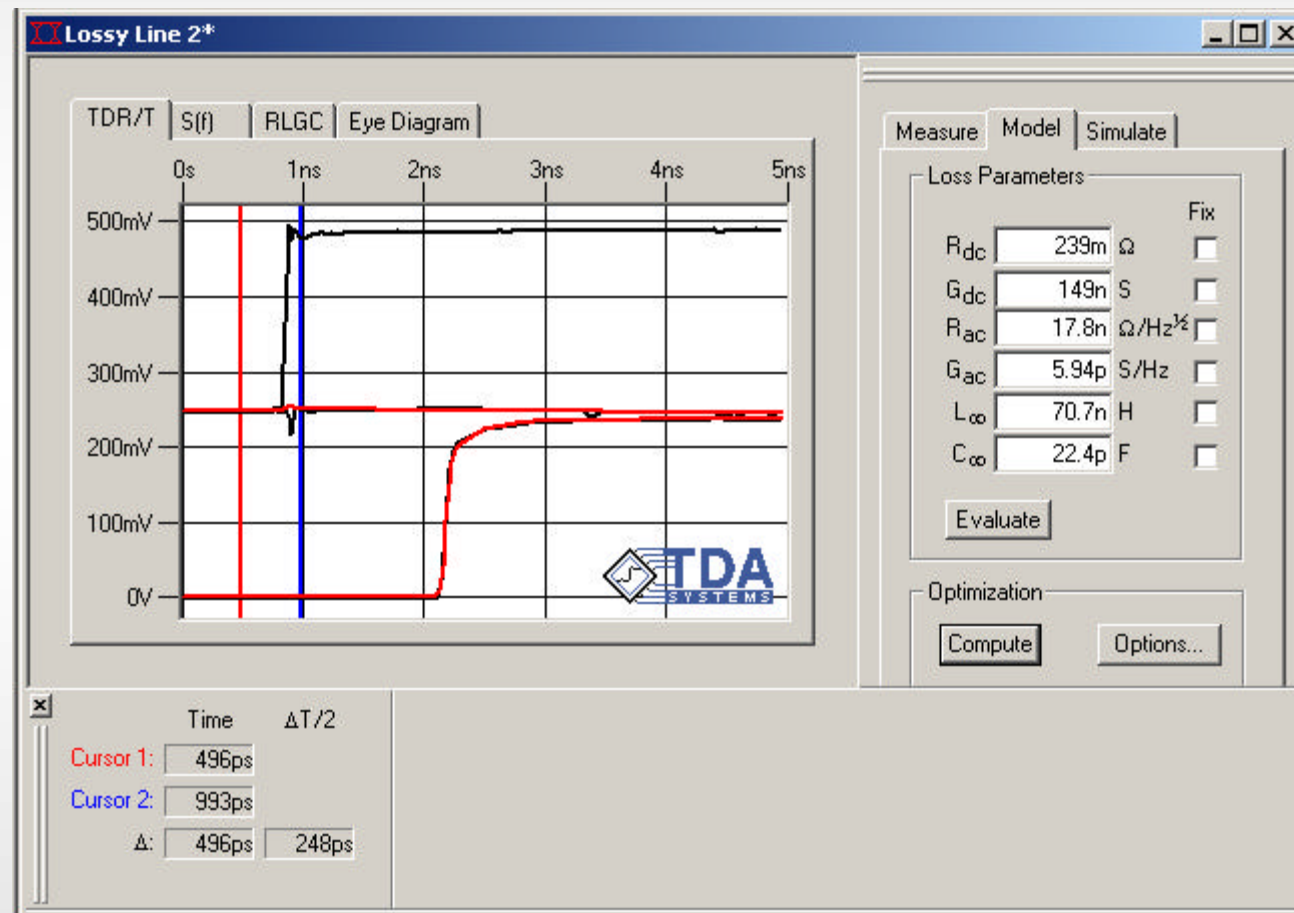
- Assume equations:

$$Z \approx R_{dc} + R_{ac} \sqrt{f} + j\omega L_{\infty}$$

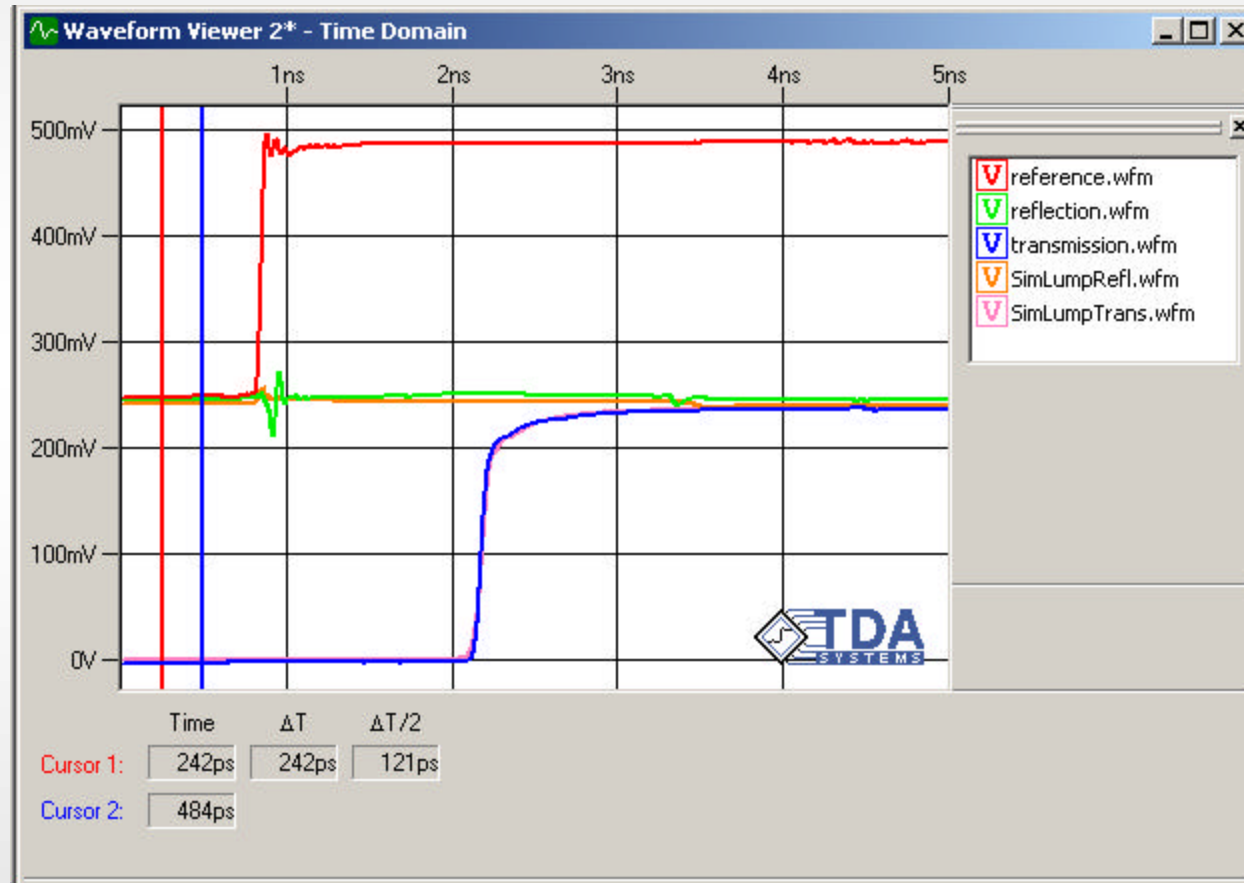
$$Y \approx G_{dc} + G_{ac} f + j\omega C_{\infty}$$

- Extract/Optimize loss parameters:  $R_{dc}$ ,  $R_{ac}$ ,  $G_{dc}$ ,  $G_{ac}$ ,  $L_{\infty}$ ,  $C_{\infty}$
- Write resulting model in various formats
  - Lumped
  - Distributed with parameters
  - Distributed with RLGC data

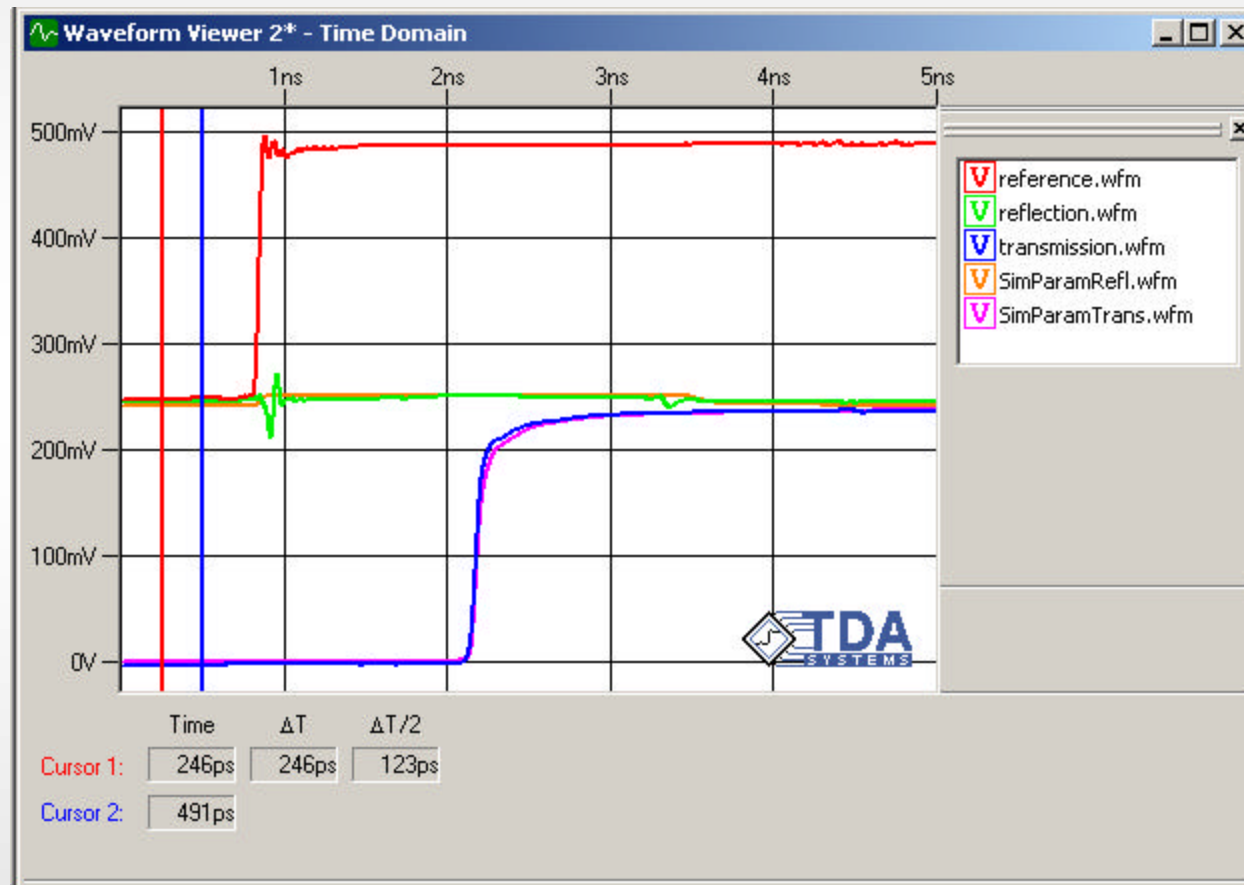
# Example: Extraction Results



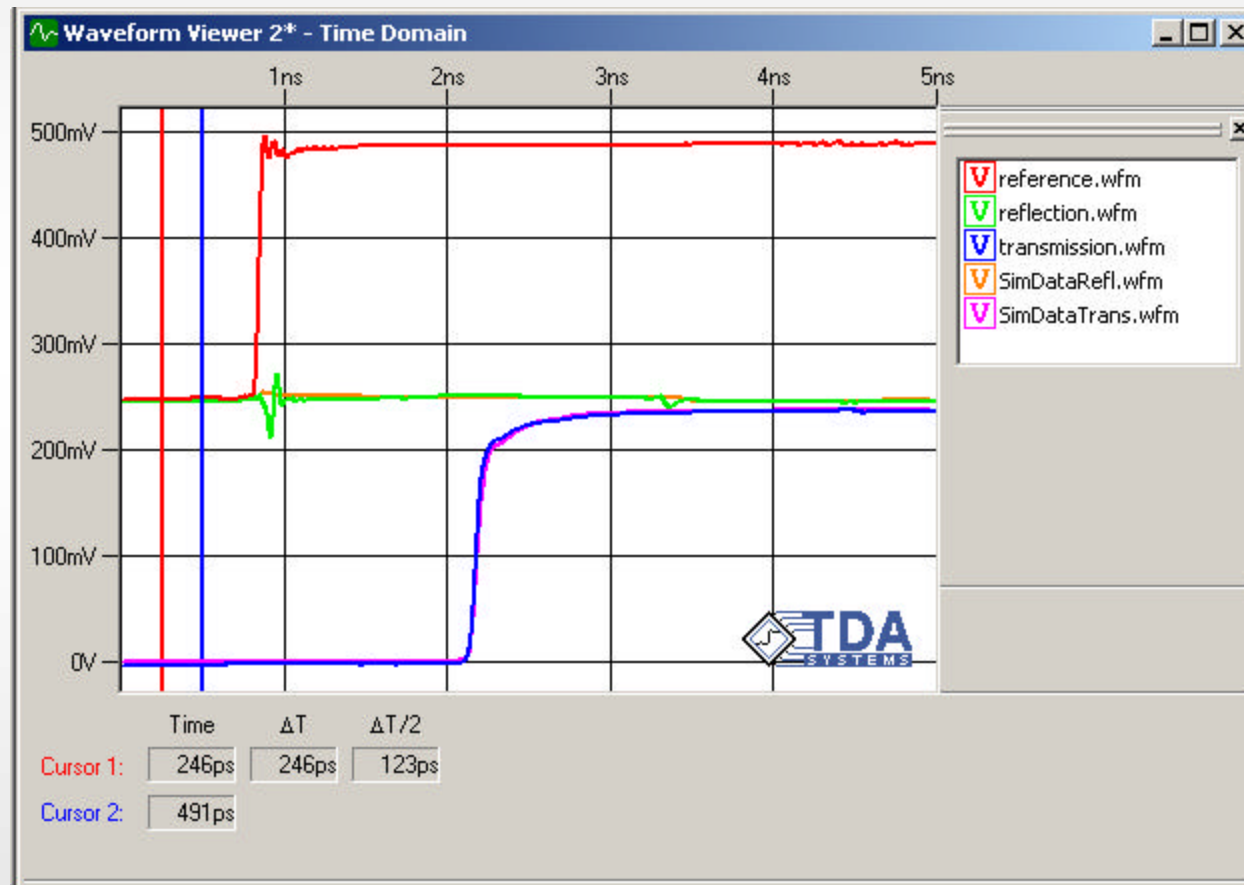
# Example: Lumped Simulation Results



# Example: Parameterized Simulation Results



# Example: RLGC Data Simulation Results



# Conclusions

---

- **Industry needs lossy line models for board-level simulation**
- **The capability exists for accurate modeling**
  - **Lumped elements, parameters, RLGC data**
  - **Our modeling approach is based on TDR measurements**
- **Care is required to ensure that models are physical and algorithms are stable**